

4-Mbit (256K words × 16 bit) Static RAM

Features

■ High speed

 $t_{AA} = 10 \text{ ns} / 15 \text{ ns}$

■ Low active and standby currents

□ Active current: I_{CC} = 38-mA typical
 □ Standby current: I_{SB2} = 6-mA typical

■ Operating voltage range: 1.65 V to 2.2 V, 2.2 V to 3.6 V, and

4.5 V to 5.5 V

■ 1.0-V data retention

■ TTL-compatible inputs and outputs

Pb-free 44-pin SOJ, 44-pin TSOP II, and 48-ball VFBGA packages

Functional Description

CY7C1041GN is high-performance CMOS fast static RAM Organized as 256K words by 16-bits.

Data writes are performed by asserting the Chip Enable (\overline{CE}) and Write Enable (WE) inputs LOW, while providing the data on I/O $_0$ through I/O $_{15}$ and address on A $_0$ through A $_{17}$ pins. The Byte High Enable (BHE) and Byte Low Enable (BLE) inputs control write operations to the upper and lower bytes of the specified memory location. BHE controls I/O $_8$ through I/O $_{15}$ and BLE controls I/O $_0$ through I/O $_7$.

Data reads are performed by asserting the Chip Enable (CE) and Output Enable (\overline{OE}) inputs LOW and providing the required address on the address lines. Read data is accessible on the I/O lines (I/O₀ through I/O₁₅). Byte accesses <u>can</u> be <u>performed</u> by asserting the required byte enable signal (BHE or BLE) to read either the upper byte or the lower byte of data from the specified address location.

All I/Os (I/O $_0$ through I/O $_{15}$) are placed in a high-impedance state during the following events:

- The device is deselected (CE HIGH)
- The control signals (OE, BLE, BHE) are de-asserted

The logic block diagram is on page 2.

Product Portfolio

			Speed	Power Dissipation					
Product	Range	V _{CC} Range (V)	Speed (ns)	Operating I_{CC} , (mA) $f = f_{max}$		Standby I (mA)			
Floudet	Kalige	VCC Range (V)	10/15			Standby, I _{SB2} (mA)			
			10/13	Typ ^[1]	Max	Typ ^[1]	Max		
CY7C1041GN18		1.65 V-2.2 V	15	-	40				
CY7C1041GN30	Industrial	2.2 V-3.6 V	10	38	45	6	8		
CY7C1041GN		4.5 V–5.5 V	10	38	45				

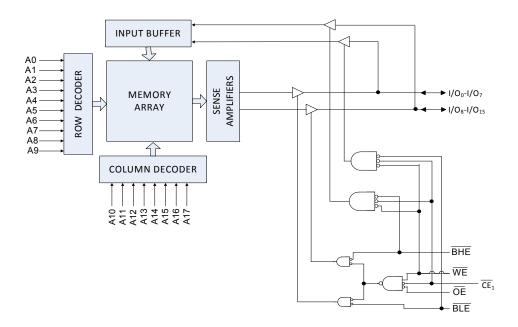
Notes

Revised September 9, 2016

Typical values are included only for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for a V_{CC} range of 1.65 V-2.2 V), V_{CC} = 3 V (for a V_{CC} range of 2.2 V-3.6 V), and V_{CC} = 5 V (for a V_{CC} range of 4.5 V-5.5 V), T_A = 25 °C.



Logic Block Diagram - CY7C1041GN





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Pin Configurations

Figure 1. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Package/Grade ID: $\mathrm{BVXI}^{[2,\ 3]}$

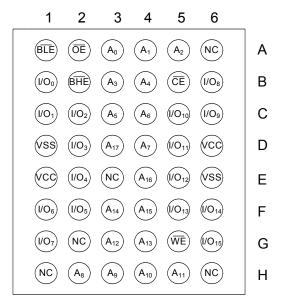


Figure 2. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Package/Grade ID: BVJXI^[2]

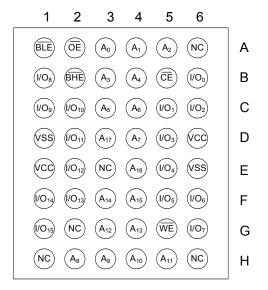
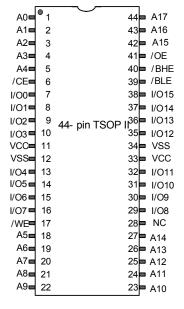


Figure 3. 44-pin TSOP II / 44-pin SOJ pinout^[2]



- 2. NC pins are not connected internally to the die.
- 3. Package type BVJXI is JEDEC compliant compared to package type BVXI. The difference between the two is that the higher and lower byte I/Os (I/O_[7:0] and I/O_[15:8] balls are swapped.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Current into outputs (in LOW state)2	0 mA
Static discharge voltage	
(MIL-STD-883, Method 3015)>20)01 V
Latch-up current> 14	0 mA

Operating Range

Grade	Ambient Temperature	V _{CC}
Industrial	–40 °C to +85 °C	1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V

DC Electrical Characteristics

Over the operating range of -40 °C to 85 °C

Damamatan	Description		Took Conditi		1	10 ns / 15 ns	S	Unit	
Parameter	Descri	ption	Test Conditions		Min	Typ ^[5]	Max	Unit	
		1.65 V to 2.2 V	V _{CC} = Min, I _{OH} = -0.1 mA		1.4	_	-		
		2.2 V to 2.7 V	V_{CC} = Min, I_{OH} = -1.0 mA		2	_	_		
	Output HIGH	2.7 V to 3.0 V	V_{CC} = Min, I_{OH} = -4.0 mA		2.2	_	-	V	
V _{OH}	voltage	3.0 V to 3.6 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 mA		2.4	-	-	V	
		4.5 V to 5.5 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 mA		2.4	_	_		
		4.5 V to 5.5 V	V_{CC} = Min, I_{OH} = -0.1 mA		$V_{CC} - 0.5^{[6]}$	_	-		
		1.65 V to 2.2 V	V_{CC} = Min, I_{OL} = 0.1 mA		-	-	0.2		
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	Output LOW	2.2 V to 2.7 V	V _{CC} = Min, I _{OL} = 2 mA		-	_	0.4	V	
V _{OL}	voltage	2.7 V to 3.6 V	V _{CC} = Min, I _{OL} = 8 mA	-	-	0.4	v		
		4.5 V to 5.5 V	V _{CC} = Min, I _{OL} = 8 mA		-	_	0.4		
	Input HIGH voltage	1.65 V to 2.2 V	-		1.4	-	V _{CC} + 0.2 ^[4]		
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		2.2 V to 2.7 V	-		2	-	$V_{CC} + 0.3^{[4]}$	V	
V _{IH}		2.7 V to 3.6 V	-	2	_	$V_{CC} + 0.3^{[4]}$	v		
		4.5 V to 5.5 V	-		2	-	V _{CC} + 0.5 ^[4]		
		1.65 V to 2.2 V	-		-0.2 ^[4]	-	0.4		
M	Input LOW voltage	2.2 V to 2.7 V	_		-0.3 ^[4]	-	0.6		
V _{IL}	Imput LOW voltage	2.7 V to 3.6 V	-		-0.3 ^[4]	-	0.8	- V	
		4.5 V to 5.5 V	_		-0.5 ^[4]	_	0.8		
I _{IX}	Input leakage curre	ent	$GND \le V_{IN} \le V_{CC}$		-1	-	+1	μА	
I _{OZ}	Output leakage cur	rent	GND \leq V _{OUT} \leq V _{CC} , Outp	-1	_	+1	μА		
	Operating aupply o	urrant	Max V _{CC} , I _{OUT} = 0 mA, CMOS levels	f = 100 MHz	_	38	45	mA	
I _{CC}	Operating supply c	urreill	CMOS levels	f = 66.7 MHz	-	_	40	IIIA	
I _{SB1}	Automatic CE power-down current – TTL inputs		$\begin{array}{c} \text{Max V}_{CC}, \overline{CE} \geq V_{IH}, \\ V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, f = \end{array}$	f _{MAX}	_	-	15	mA	
I _{SB2}	Automatic CE power CMOS inputs	er-down current –	$\begin{array}{c} \text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.2 \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or V}_{\text{IN}} \end{array}$	V, <u>c</u> 0.2 V, f = 0	_	6	8	mA	

^{4.} $V_{IL(min)}$ = -2.0 V and $V_{IH(max)}$ = V_{CC} + 2 V for pulse durations of less than 20 ns.

^{5.} Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for V_{CC} range of 1.65 V–2.2 V), V_{CC} = 3 V (for V_{CC} range of 2.2 V–3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V–5.5 V), T_A = 25 °C.

^{6.} This parameter is guaranteed by design and not tested.



Capacitance

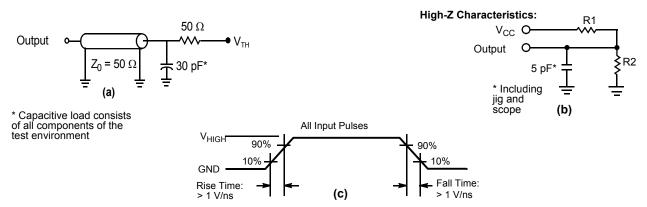
Parameter ^[7]	Description	Test Conditions	48-ball VFBGA	44-pin SOJ	44-pin TSOP II	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz,	10	10	10	pF
C _{OUT}	I/O capacitance	$V_{CC} = V_{CC(typ)}$	10	10	10	pF

Thermal Resistance

Parameter ^[7]	Description	Test Conditions	48-ball VFBGA	44-pin SOJ	44-pin TSOP II	Unit
I(H)	(and the control of	Still air, soldered on a 3 × 4.5 inch, four-layer	31.35	55.37	68.85	°C/W
(H) 10	T	printed circuit board	14.74	30.41	15.97	°C/W

AC Test Loads and Waveforms

Figure 4. AC Test Loads and Waveforms $^{[8]}$



Parameters	1.8 V	3.0 V	5.0 V	Unit
R1	1667	317	317	Ω
R2	1538	351	351	Ω
V _{TH}	0.9	1.5	1.5	V
V _{HIGH}	1.8	3	3	V

- 7. Tested initially and after any design or process changes that may affect these parameters.
- 8. Full-device AC operation assumes a 100- μ s ramp time from 0 to $V_{CC(min)}$ and a 100- μ s wait time after V_{CC} stabilization.



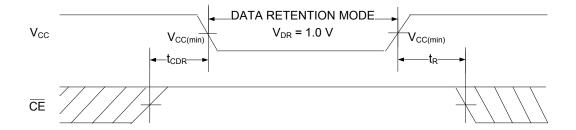
Data Retention Characteristics

Over the operating range of –40 $^{\circ}$ C to 85 $^{\circ}$ C

Parameter	Description	Conditions	Min	Max	Unit
V_{DR}	V _{CC} for data retention		1	-	V
I _{CCDR}	Data retention current	$V_{CC} = 1.2 \text{ V}, \overline{CE} \ge V_{CC} - 0.2 \text{ V}^{[9]},$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}, \text{ or } V_{IN} \le 0.2 \text{ V}$	-	8	mA
t _{CDR} ^[10]	Chip deselect to data retention time		0	_	ns
t _R ^[9, 10]	Operation recovery time	V _{CC} ≥ 2.2 V	10	_	ns
	Operation recovery time	V _{CC} < 2.2 V	15	_	ns

Data Retention Waveform

Figure 5. Data Retention Waveform^[9]



^{9.} Full-device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \ge 100 \, \mu s$ or stable at $V_{CC \, (min)} \ge 100 \, \mu s$.

^{10.} These parameters are guaranteed by design.



AC Switching Characteristics

Over the operating range of -40 °C to 85 °C

Parameter ^[11]	Description	10	10 ns			11!4
Parameter	Description	Min	Max	Min	Max	Unit
Read Cycle			•	•	•	
t _{RC}	Read cycle time	10	-	15	_	ns
t _{AA}	Address to data	_	10	-	15	ns
t _{OHA}	Data hold from address change	3	-	3	_	ns
t _{ACE}	CE LOW to data ^[12]	_	10	-	15	ns
t _{DOE}	OE LOW to data	_	4.5	-	8	ns
t _{LZOE}	OE LOW to low impedance ^[13, 14]	0	-	0	_	ns
t _{HZOE}	OE HIGH to HI-Z ^[13, 14]	_	5	-	8	ns
t _{LZCE}	CE LOW to low impedance ^[12, 13, 14]	3	-	3	_	ns
t _{HZCE}	CE HIGH to HI-Z ^[12, 13, 14]	_	5	-	8	ns
t _{PU}	CE LOW to power-up ^[12, 14, 15]	0	-	0	_	ns
t _{PD}	CE HIGH to power-down ^[12, 14, 15]	-	10	-	15	ns
t _{DBE}	Byte enable to data valid	_	4.5	-	8	ns
t _{LZBE}	Byte enable to low impedance ^[14]	0	-	0	_	ns
t _{HZBE}	Byte disable to HI-Z ^[14]	_	6	-	8	ns
Write Cycle ^{[15}	5, 16]					•
t _{WC}	Write cycle time	10	_	15	_	ns
t _{SCE}	CE LOW to write end [12]	7	_	12	_	ns
t _{AW}	Address setup to write end	7	_	12	_	ns
t _{HA}	Address hold from write end	0	_	0	_	ns
t _{SA}	Address setup to write start	0	_	0	_	ns
t _{PWE}	WE pulse width	7	_	12	_	ns
t _{SD}	Data setup to write end	5	_	8	_	ns
t _{HD}	Data hold from write end	0	-	0	_	ns
t _{LZWE}	WE HIGH to low impedance [13, 14]	3	-	3	_	ns
t _{HZWE}	WE LOW to HI-Z [13, 14]	_	5	-	8	ns
t _{BW}	Byte Enable to write end	7	_	12	_	ns

^{11.} Test conditions assume a signal transition time (rise/fall) of 3 ns or less, timing reference levels of 1.5 V (for $V_{CC} \ge 3$ V) and $V_{CC}/2$ (for $V_{CC} < 3$ V), and input pulse levels of 0 to 3 V (for $V_{CC} \ge 3$ V) and 0 to V_{CC} (for $V_{CC} < 3$ V). Test conditions for the read cycle use output loading, as shown in part (a) of Figure 4 on page 6, unless specified otherwise.

^{12.} For all dual chip enable devices, $\overline{\text{CE}}$ is the logical combination of $\overline{\text{CE}}_1$ and $\overline{\text{CE}}_2$. When $\overline{\text{CE}}_1$ is LOW and $\overline{\text{CE}}_2$ is HIGH, $\overline{\text{CE}}$ is LOW; when $\overline{\text{CE}}_1$ is HIGH or $\overline{\text{CE}}_2$ is LOW, $\overline{\text{CE}}$ is HIGH.

^{13.} t_{HZOE}, t_{HZOE}, t_{HZOE}, t_{LZOE}, t_{LZOE}, t_{LZOE}, t_{LZOE}, and t_{LZBE} are specified with a load capacitance of 5 pF, as shown in part (b) of Figure 4 on page 6. Transition is measured ±200 mV from steady state voltage.

^{14.} These parameters are guaranteed by design and are not tested.

^{15.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

^{16.} The minimum write cycle pulse width in Write Cycle No. 2 (WE Controlled, $\overline{\text{OE}}$ LOW) should be equal to sum of t_{ND} and t_{HZWE} .



Switching Waveforms

Figure 6. Read Cycle No. 1 (Address Transition Controlled)[17, 18]

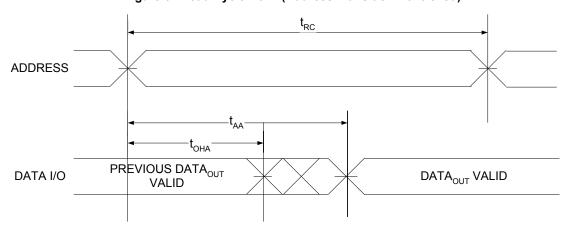
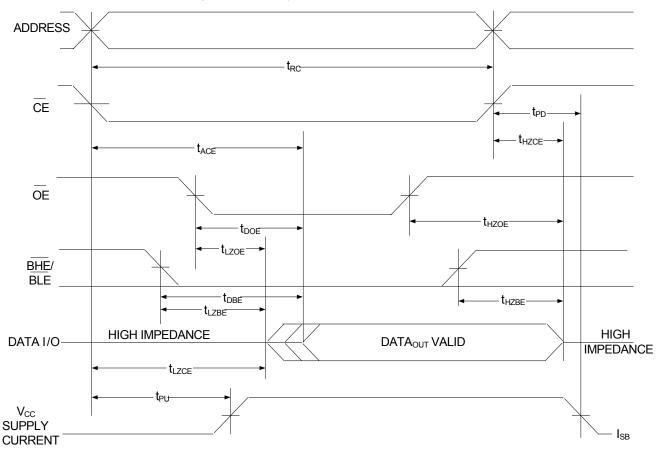


Figure 7. Read Cycle No. 2 ($\overline{\text{OE}}$ Controlled)[18, 19]



- 17. The device is continuously selected, $\overline{OE} = V_{|L}$, $\overline{CE} = V_{|L}$, \overline{BHE} or \overline{BLE} or both = $V_{|L}$.
- 18. WE is HIGH for the read cycle.
- 19. Address valid prior to or coincident with $\overline{\text{CE}}$ LOW transition.



Switching Waveforms (continued)

Figure 8. Write Cycle No. 1 ($\overline{\text{CE}}$ Controlled)[20, 21]

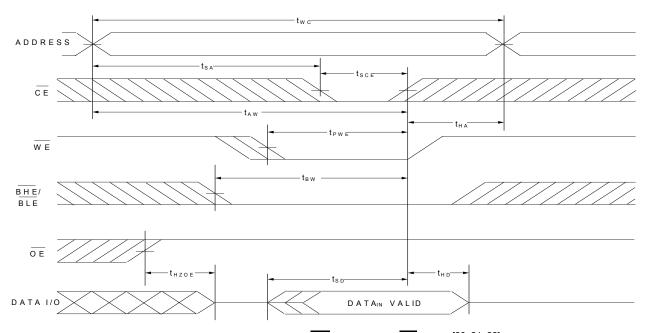
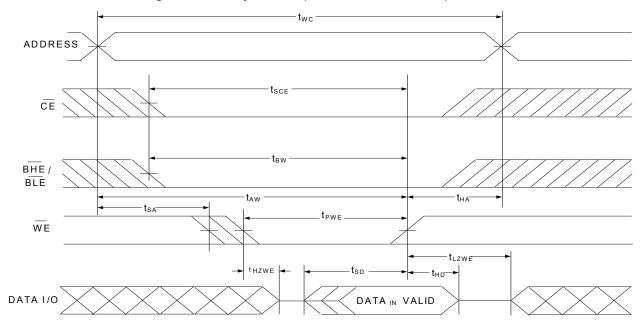


Figure 9. Write Cycle No. 2 (WE Controlled, $\overline{\text{OE}}$ LOW)[20, 21, 22]



- 20. The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 21. Data I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$, or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.
- 22. The minimum write cycle pulse width should be equal to sum of $t_{\mbox{\footnotesize SD}}$ and $t_{\mbox{\footnotesize HZWE}}$



Switching Waveforms (continued)

ADDRESS

Telegrater 10. Write Cycle No. 3 (BLE or BHE Controlled)

Telegrater 10. Write Cycle No. 3 (BLE or BHE Controlled)

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Telegrater 10. Write Cycle No. 3 (BLE or BHE Controlled)

Telegra

ADDRESS

CE1

Thyc

tsc

tsc

tsc

thyc

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- 23. The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 24. Data I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$, or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.
- 25. Data I/O is high impedance if $\overline{OE} = V_{IH}$.
- 26. During this period the I/Os are in output state. Do not apply input signals.



Truth Table

CE	ŌE	WE	BLE	BHE	I/O ₀ -I/O ₇	I/O ₈ -I/O ₁₅	Mode	Power
Н	X ^[27]	X ^[27]	X ^[27]	X ^[27]	HI-Z	HI-Z	Power down	Standby (I _{SB})
L	L	Н	L	L	Data out	Data out	Read all bits	Active (I _{CC})
L	L	Н	L	Н	Data out	HI-Z	Read lower bits only	Active (I _{CC})
L	L	Н	Н	L	HI-Z	Data out	Read upper bits only	Active (I _{CC})
L	Х	L	L	L	Data in	Data in	Write all bits	Active (I _{CC})
L	Х	L	L	Н	Data in	HI-Z	Write lower bits only	Active (I _{CC})
L	Х	L	Н	L	HI-Z	Data in	Write upper bits only	Active (I _{CC})
L	Н	Н	Х	Х	HI-Z	HI-Z	Selected, outputs disabled	Active (I _{CC})

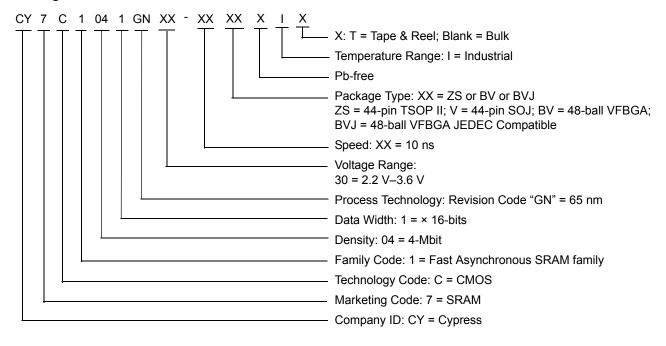
Notes 27. The input voltage levels on these pins should be either at V_{IH} or V_{IL} .



Ordering Information

Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (all Pb-free)	Operating Range
	2.2 V-3.6 V	CY7C1041GN30-10ZSXI	51-85087	44-pin TSOP II	- Industrial
		CY7C1041GN30-10ZSXI	51-85087	44-pin TSOP II, Tape & Reel	
		CY7C1041GN30-10VXI	51-85082	44-pin SOJ	
		CY7C1041GN30-10VXIT	51-85082	44-pin SOJ, Tape & Reel	
		CY7C1041GN30-10BVXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm)	
10		CY7C1041GN30-10BVXIT	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), Tape & Reel	
10		CY7C1041GN30-10BVJXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), JEDEC Compatible	
		CY7C1041GN30-10BVJXIT	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), JEDEC Compatible, Tape & Reel	
	4.5 V–5.5 V	CY7C1041GN-10ZSXI	51-85087	44-pin TSOP II	
		CY7C1041GN-10ZSXIT	51-85087	44-pin TSOP II, Tape & Reel	
		CY7C1041GN-10VXI	51-85082	44-pin SOJ	
		CY7C1041GN-10VXIT	51-85082	44-pin SOJ, Tape & Reel	

Ordering Code Definitions





Package Diagrams

Figure 12. 44-pin TSOP II (Z44) Package Outline, 51-85087

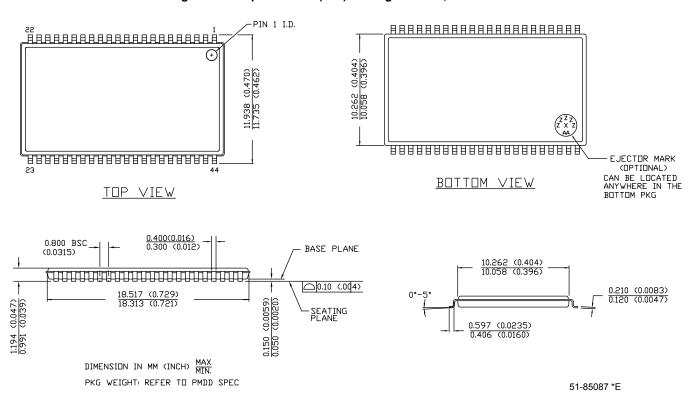
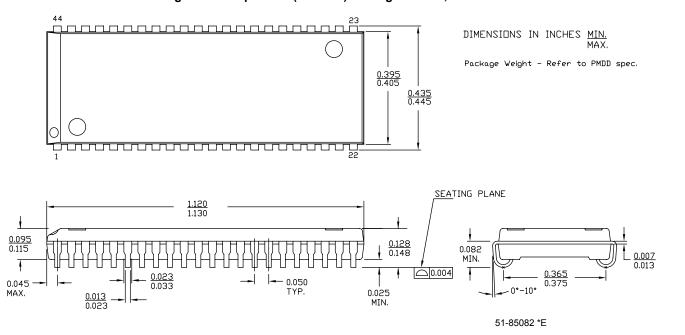


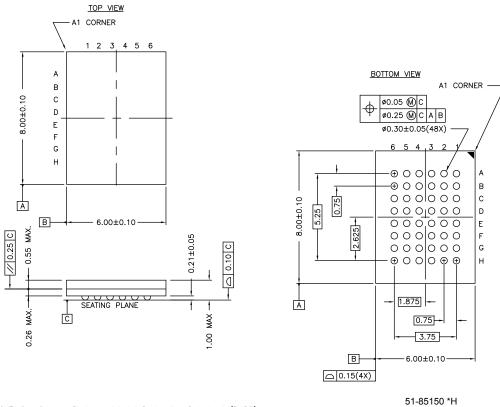
Figure 13. 44-pin SOJ (400 Mils) Package Outline, 51-85082





Package Diagrams (continued)

Figure 14. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150



NOTE:
PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD)
posted on the Cypress web.



Acronyms

Acronym	Description			
BHE	byte high enable			
BLE	byte low enable			
CE	chip enable			
CMOS	complementary metal oxide semiconductor			
I/O	input/output			
ŌĒ	output enable			
SRAM	static random-access memory			
TSOP	thin small outline package			
TTL	transistor-transistor logic			
VFBGA	very fine-pitch ball grid array			
WE	write enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure				
°C	Degrees Celsius				
MHz	megahertz				
μΑ	microamperes				
μS	microseconds				
mA	milliamperes				
mm	millimeters				
ns	nanoseconds				
Ω	ohms				
%	percent				
pF	picofarads				
V	volts				
W	watts				



Document History Page

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Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change				
**	5074414	NILE	01/06/2016	New data sheet.				
*A	5082573	NILE	01/12/2016	Updated Logic Block Diagram – CY7C1041GN. Updated Ordering Information: Updated part numbers.				
*B	5120171	VINI	02/01/2016	Updated Logic Block Diagram – CY7C1041GN.				
*C	5322961	VINI	06/24/2016	Updated Ordering Information: Updated part numbers. Updated to new template.				
*D	5431651	NILE	09/09/2016	Updated Ordering Information: Updated part numbers. Added Tape & Reel ordering codes. Updated DC Electrical Characteristics: Enhanced V _{OH} for voltage range 3.0V to 3.6V from 2.2V to 2.4V. Enhanced V _{IH} for voltage range 4.5V to 5.5V from 2.2V to 2.0V. Updated Note 4. Updated Copyright and Disclaimer.				



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